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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	32200
Number of Logic Elements/Cells	412160
Total RAM Bits	32440320
Number of I/O	350
Number of Gates	-
Voltage - Supply	0.97V ~ 1.03V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1156-BBGA, FCBGA
Supplier Device Package	1158-FCBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc7vx415t-2ff1158i

Table 1: Absolute Maximum Ratings⁽¹⁾ (Cont'd)

Symbol	Description	Min	Max	Units
$V_{MGTAVTTRCAL}$	Analog supply voltage for the resistor calibration circuit of the GTX/GTH transceiver column	-0.5	1.32	V
V_{IN}	Receiver (RXP/RXN) and Transmitter (TXP/TXN) absolute input voltage	-0.5	1.26	V
I_{DCIN}	DC input current for receiver input pins DC coupled $V_{MGTAVTT} = 1.2V$	–	14	mA
I_{DCOUT}	DC output current for transmitter pins DC coupled $V_{MGTAVTT} = 1.2V$	–	14	mA
XADC				
V_{CCADC}	XADC supply relative to GNDADC	-0.5	2.0	V
V_{REFP}	XADC reference input relative to GNDADC	-0.5	2.0	V
Temperature				
T_{STG}	Storage temperature (ambient)	-65	150	°C
T_{SOL}	Maximum soldering temperature for Pb/Sn component bodies ⁽⁶⁾	–	+220	°C
	Maximum soldering temperature for Pb-free component bodies ⁽⁶⁾	–	+260	°C
T_j	Maximum junction temperature ⁽⁶⁾	–	+125	°C

Notes:

- Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time might affect device reliability.
- The lower absolute voltage specification always applies.
- For I/O operation, refer to the *7 Series FPGAs SelectIO Resources User Guide* (UG471).
- The maximum limit applies to DC signals. For maximum undershoot and overshoot AC specifications, see Table 4 and Table 5.
- See Table 10 for TMD5_33 specifications.
- For soldering guidelines and thermal considerations, see the *7 Series FPGA Packaging and Pinout Specification* (UG475).

Table 2: Recommended Operating Conditions⁽¹⁾⁽²⁾

Symbol	Description	Min	Typ	Max	Units
FPGA Logic					
$V_{CCINT}^{(3)}$	Internal supply voltage	0.97	1.00	1.03	V
	Internal supply voltage for -1C devices with voltage identification (VID) bit programmed to run at 0.9V typical ⁽⁴⁾ .	0.87	0.90	0.93	V
$V_{CCBRAM}^{(3)}$	Block RAM supply voltage	0.97	1.00	1.03	V
	Block RAM supply voltage for -1C devices with voltage identification (VID) bit programmed to run at 0.9V typical ⁽⁴⁾ .	0.87	0.90	1.03	V
V_{CCAUX}	Auxiliary supply voltage	1.71	1.80	1.89	V
$V_{CCO}^{(5)(6)}$	Supply voltage for 3.3V HR I/O banks	1.14	–	3.465	V
	Supply voltage for 1.8V HP I/O banks	1.14	–	1.89	V
V_{CCAUX_IO}	Auxiliary supply voltage when set to 1.8V	1.71	1.80	1.89	V
	Auxiliary supply voltage when set to 2.0V	1.94	2.00	2.06	V
$V_{IN}^{(7)}$	I/O input voltage	-0.20	–	$V_{CCO} + 0.2$	V
	I/O input voltage (when $V_{CCO} = 3.3V$) for V_{REF} and differential I/O standards except TMD5_33 ⁽⁸⁾	-0.20	–	2.625	V
$I_{IN}^{(9)}$	Maximum current through any pin in a powered or unpowered bank when forward biasing the clamp diode.	–	–	10	mA
$V_{CCBATT}^{(10)}$	Battery voltage	1.0	–	1.89	V

Table 6: Typical Quiescent Supply Current (Cont'd)

Symbol	Description	Device	Speed Grade			Units
			-3	-2/-2L/-2G	-1	
I _{CCAUXQ}	Quiescent V _{CCAUX} supply current	XC7V585T	114	114	114	mA
		XC7V2000T	N/A	315	315	mA
		XC7VX330T	73	73	73	mA
		XC7VX415T	88	88	88	mA
		XC7VX485T	104	104	104	mA
		XC7VX550T	147	147	147	mA
		XC7VX690T	147	147	147	mA
		XC7VX980T	N/A	183	183	mA
		XC7VX1140T	N/A	250	250	mA
I _{CCAUX_IOQ}	Quiescent V _{CCAUX_IO} supply current	XC7V585T	2	2	2	mA
		XC7V2000T	N/A	2	2	mA
		XC7VX330T	2	2	2	mA
		XC7VX415T	2	2	2	mA
		XC7VX485T	2	2	2	mA
		XC7VX550T	2	2	2	mA
		XC7VX690T	2	2	2	mA
		XC7VX980T	N/A	2	2	mA
		XC7VX1140T	N/A	2	2	mA
I _{CCBRAMQ}	Quiescent V _{CCBRAM} supply current	XC7V585T	34	34	34	mA
		XC7V2000T	N/A	56	56	mA
		XC7VX330T	32	32	32	mA
		XC7VX415T	38	38	38	mA
		XC7VX485T	44	44	44	mA
		XC7VX550T	63	63	63	mA
		XC7VX690T	63	63	63	mA
		XC7VX980T	N/A	65	65	mA
		XC7VX1140T	N/A	81	81	mA

Notes:

1. Typical values are specified at nominal voltage, 85°C junction temperatures (T_j) with single-ended SelectIO resources.
2. Typical values are for blank configured devices with no output current loads, no active input pull-up resistors, all I/O pins are 3-state and floating.
3. Use the Xilinx Power Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate static power consumption for conditions other than those specified.

Table 7 shows the minimum current, in addition to I_{CCQ} , that is required by Virtex-7 T and XT devices for proper power-on and configuration. If the current minimums shown in Table 6 and Table 7 are met, the device powers on after all five supplies have passed through their power-on reset threshold voltages. The FPGA must not be configured until after V_{CCINT} is applied.

Once initialized and configured, use the XPower tools to estimate current drain on these supplies.

Table 7: Power-On Current for Virtex-7 T and XT Devices

Device	$I_{CCINTMIN}$ Typ ⁽¹⁾	$I_{CCAUXMIN}$ Typ ⁽¹⁾	I_{CCOMIN} Typ ⁽¹⁾	I_{CCAUX_IO} Typ ⁽¹⁾	I_{CCBRAM} Typ ⁽¹⁾	Units
XC7V585T	$I_{CCINTQ} + 2700$	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 60$ mA per bank	$I_{CCOAXIOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 108$	mA
XC7V2000T	$I_{CCINTQ} + 4000$	$I_{CCAUXQ} + 80$	$I_{CCOQ} + 60$ mA per bank	$I_{CCOAXIOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 176$	mA
XC7VX330T	$I_{CCINTQ} + 1000$	$I_{CCAUXQ} + 65$	$I_{CCOQ} + 40$ mA per bank	$I_{CCOAXIOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 95$	mA
XC7VX415T	$I_{CCINTQ} + 1200$	$I_{CCAUXQ} + 75$	$I_{CCOQ} + 40$ mA per bank	$I_{CCOAXIOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 115$	mA
XC7VX485T	$I_{CCINTQ} + 1200$	$I_{CCAUXQ} + 80$	$I_{CCOQ} + 40$ mA per bank	$I_{CCOAXIOQ} + 40$ mA per bank	$I_{CCBRAMQ} + 140$	mA
XC7VX550T	$I_{CCINTQ} + 3300$	$I_{CCAUXQ} + 143$	$I_{CCOQ} + 40$ mA per bank	$I_{CCOAXIOQ} + 57$ mA per bank	$I_{CCBRAMQ} + 200$	mA
XC7VX690T	$I_{CCINTQ} + 3300$	$I_{CCAUXQ} + 143$	$I_{CCOQ} + 40$ mA per bank	$I_{CCOAXIOQ} + 57$ mA per bank	$I_{CCBRAMQ} + 200$	mA
XC7VX980T	$I_{CCINTQ} + 6500$	$I_{CCAUXQ} + 202$	$I_{CCOQ} + 40$ mA per bank	$I_{CCOAXIOQ} + 60$ mA per bank	$I_{CCBRAMQ} + 204$	mA
XC7VX1140T	$I_{CCINTQ} + 8000$	$I_{CCAUXQ} + 235$	$I_{CCOQ} + 40$ mA per bank	$I_{CCOAXIOQ} + 63$ mA per bank	$I_{CCBRAMQ} + 256$	mA

Notes:

- Typical values are specified at nominal voltage, 25°C.
- Use the Xilinx Power Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate maximum power-on currents.

Table 8: Power Supply Ramp Time

Symbol	Description	Conditions	Min	Max	Units
T_{VCCINT}	Ramp time from GND to 90% of V_{CCINT}		0.2	50	ms
T_{VCCO}	Ramp time from GND to 90% of V_{CCO}		0.2	50	ms
T_{VCCAUX}	Ramp time from GND to 90% of V_{CCAUX}		0.2	50	ms
T_{VCCAUX_IO}	Ramp time from GND to 90% of V_{CCAUX_IO}		0.2	50	ms
$T_{VCCBRAM}$	Ramp time from GND to 90% of V_{CCBRAM}		0.2	50	ms
$T_{VCCO2VCCAUX}$	Allowed time per power cycle for $V_{CCO} - V_{CCAUX} > 2.625V$	$T_J = 100^{\circ}C^{(1)}$	–	500	ms
		$T_J = 85^{\circ}C^{(1)}$	–	800	
$T_{MGTAVCC}$	Ramp time from GND to 90% of $V_{MGTAVCC}$		0.2	50	ms
$T_{MGTAVTT}$	Ramp time from GND to 90% of $V_{MGTAVTT}$		0.2	50	ms
$T_{MGTVCCAUX}$	Ramp time from GND to 90% of $V_{MGTVCCAUX}$		0.2	50	ms

Notes:

- Based on 240,000 power cycles with nominal V_{CCO} of 3.3V or 36,500 power cycles with a worst case V_{CCO} of 3.465V.

Speed Grade Designations

Since individual family members are produced at different times, the migration from one category to another depends completely on the status of the fabrication process for each device. Table 15 correlates the current status of each Virtex-7 T and XT device on a per speed grade basis.

Table 15: Virtex-7 T and XT Device Speed Grade Designations

Device	Speed Grade Designations		
	Advance	Preliminary	Production
XC7V585T			-3, -2, -2L, -1
XC7V2000T	-2L, -2G		-2, -1
XC7VX330T			-3, -2, -2L, -1
XC7VX415T			-3, -2, -2L, -1
XC7VX485T			-3, -2, -2L, -1
XC7VX550T			-3, -2, -2L, -1
XC7VX690T			-3, -2, -2L, -1
XC7VX980T	-2, -2L, -1		
XC7VX1140T	-2, -2L, -2G, -1		

Production Silicon and Software Status

In some cases, a particular family member (and speed grade) is released to production before a speed specification is released with the correct label (Advance, Preliminary, Production). Any labeling discrepancies are corrected in subsequent speed specification releases.

Table 16 lists the production released Virtex-7 T and XT device, speed grade, and the minimum corresponding supported speed specification version and software revisions. The software and speed specifications listed are the minimum releases required for production. All subsequent releases of software and speed specifications are valid.

Table 16: Virtex-7 T and XT Device Production Software and Speed Specification Release

Device	Speed Grade Designations				
	-3	-2G	-2	-2L	-1
XC7V585T	Vivado 2012.4 v1.08 or ISE 14.2 v1.06	N/A	Vivado 2012.4 v1.08 or ISE 14.2 v1.06		
XC7V2000T	N/A		Vivado 2012.4 v1.07		Vivado 2012.4 v1.07
XC7VX330T	Vivado 2013.1 v1.08 or ISE 14.5 v1.08	N/A	Vivado 2013.1 v1.08 or ISE 14.5 v1.08		
XC7VX415T		N/A			
XC7VX485T	Vivado 2012.4 v1.08 or ISE 14.2 v1.06	N/A	Vivado 2012.4 v1.08 or ISE 14.2 v1.06		
XC7VX550T	Vivado 2013.1 v1.08 or ISE 14.5 v1.08	N/A	Vivado 2013.1 v1.08 or ISE 14.5 v1.08		
XC7VX690T	Vivado 2013.1 v1.08 or ISE 14.5 v1.08	N/A	Vivado 2013.1 v1.08 or ISE 14.5 v1.08		
XC7VX980T	N/A	N/A			
XC7VX1140T	N/A				

Notes:

- Blank entries indicate a device and/or speed grade in advance or preliminary status.

Performance Characteristics

This section provides the performance characteristics of some common functions and designs implemented in Virtex-7 T and XT devices. The numbers reported here are worst-case values; they have all been fully characterized. These values are subject to the same guidelines as the [AC Switching Characteristics, page 12](#). In each table, the I/O bank type is either High Performance (HP) or High Range (HR).

Table 17: Networking Applications Interface Performances

Description	I/O Bank Type	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
SDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 8)	HR	710	710	625	Mb/s
	HP	710	710	625	Mb/s
DDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 14)	HR	1250	1250	950	Mb/s
	HP	1600	1400	1250	Mb/s
SDR LVDS receiver (SFI-4.1) ⁽¹⁾	HR	710	710	625	Mb/s
	HP	710	710	625	Mb/s
DDR LVDS receiver (SPI-4.2) ⁽¹⁾	HR	1250	1250	950	Mb/s
	HP	1600	1400	1250	Mb/s

Notes:

1. LVDS receivers are typically bounded with certain applications where specific dynamic phase-alignment (DPA) algorithms dominate deterministic performance.

Table 18: Maximum Physical Interface (PHY) Rate for Memory Interfaces IP available with the Memory Interface Generator⁽¹⁾⁽²⁾

Memory Standard	I/O Bank Type	V _{CCAUX_IO}	Speed Grade			Units
			-3	-2/-2L/-2G	-1	
4:1 Memory Controllers						
DDR3	HP	2.0V	1866	1866	1600	Mb/s
	HP	1.8V	1600	1333	1066	Mb/s
	HR	N/A	1066	1066	800	Mb/s
DDR3L	HP	2.0V	1600	1600	1333	Mb/s
	HP	1.8V	1333	1066	800	Mb/s
	HR	N/A	800	800	667	Mb/s
DDR2	HP	2.0V	800	800	800	Mb/s
	HP	1.8V	800	800	800	Mb/s
	HR	N/A	800	800	800	Mb/s
RLDRAM III	HP	2.0V	800	667	667	MHz
	HP	1.8V	550	500	450	MHz
	HR	N/A	N/A			
2:1 Memory Controllers						
DDR3	HP	2.0V	1066	1066	800	Mb/s
	HP	1.8V	1066	1066	800	Mb/s
	HR	N/A	1066	1066	800	Mb/s
DDR3L	HP	2.0V	1066	1066	800	Mb/s
	HP	1.8V	1066	1066	800	Mb/s
	HR	N/A	800	800	667	Mb/s
DDR2	HP	2.0V	800	800	800	Mb/s
	HP	1.8V				
	HR	N/A				
QDR II+ ⁽³⁾	HP	2.0V	550	500	450	MHz
	HP	1.8V				
	HR	N/A	500	450	400	MHz
RLDRAM II	HP	2.0V	533	500	450	MHz
	HP	1.8V				
	HR	N/A				
LPDDR2	HP	2.0V	667	667	667	Mb/s
	HP	1.8V	667	667	667	Mb/s
	HR	N/A	667	667	667	Mb/s

Notes:

1. V_{REF} tracking is required. For more information, see the *7 Series FPGAs Memory Interface Solutions User Guide* ([UG586](#)).
2. When using the internal V_{REF} the maximum data rate is 800 Mb/s (400 MHz).
3. The maximum QDRII+ performance specifications are for burst-length 4 (BL = 4) implementations. Burst length 2 (BL = 2) implementations are limited to 333 MHz for all speed grades and I/O bank types.

IOB Pad Input/Output/3-State

Table 19 (3.3V high-range IOB (HR)) and **Table 20** (1.8V high-performance IOB (HP)) summarizes the values of standard-specific data input delay adjustments, output delays terminating at pads (based on standard) and 3-state delays.

- T_{IOPI} is described as the delay from IOB pad through the input buffer to the I-pin of an IOB pad. The delay varies depending on the capability of the SelectIO input buffer.
- T_{IOOP} is described as the delay from the O pin to the IOB pad through the output buffer of an IOB pad. The delay varies depending on the capability of the SelectIO output buffer.
- T_{IOTP} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is disabled. The delay varies depending on the SelectIO capability of the output buffer. In HP I/O banks, the internal DCI termination turn-on time is always faster than T_{IOTP} when the DCITERMDISABLE pin is used. In HR I/O banks, the IN_TERM termination turn-on time is always faster than T_{IOTP} when the INTERMDISABLE pin is used.

Table 19: 3.3V IOB High Range (HR) Switching Characteristics

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units
	Speed Grade			Speed Grade			Speed Grade			
	-3	-2/-2L/-2G	-1	-3	-2/-2L/-2G	-1	-3	-2/-2L/-2G	-1	
LVTTTL_S4	1.31	1.42	1.64	3.77	3.90	4.00	4.53	4.76	4.99	ns
LVTTTL_S8	1.31	1.42	1.64	3.50	3.64	3.73	4.26	4.50	4.72	ns
LVTTTL_S12	1.31	1.42	1.64	3.49	3.62	3.72	4.25	4.48	4.71	ns
LVTTTL_S16	1.31	1.42	1.64	3.03	3.17	3.26	3.79	4.03	4.25	ns
LVTTTL_S24	1.31	1.42	1.64	3.25	3.39	3.48	4.01	4.25	4.47	ns
LVTTTL_F4	1.31	1.42	1.64	3.22	3.36	3.45	3.98	4.22	4.44	ns
LVTTTL_F8	1.31	1.42	1.64	2.71	2.84	2.93	3.47	3.70	3.92	ns
LVTTTL_F12	1.31	1.42	1.64	2.69	2.82	2.92	3.45	3.68	3.91	ns
LVTTTL_F16	1.31	1.42	1.64	2.57	2.85	3.15	3.33	3.71	4.14	ns
LVTTTL_F24	1.31	1.42	1.64	2.41	2.64	2.89	3.17	3.50	3.88	ns
LVDS_25 ⁽¹⁾	0.64	0.68	0.80	1.36	1.47	1.55	2.12	2.33	2.54	ns
MINI_LVDS_25	0.68	0.70	0.79	1.36	1.47	1.55	2.12	2.33	2.54	ns
BLVDS_25 ⁽¹⁾	0.65	0.69	0.80	1.83	2.02	2.20	2.59	2.88	3.19	ns
RSDS_25 (point to point) ⁽¹⁾	0.63	0.68	0.79	1.36	1.48	1.55	2.12	2.34	2.54	ns
PPDS_25 ⁽¹⁾	0.65	0.69	0.80	1.36	1.49	1.58	2.12	2.35	2.57	ns
TMDS_33 ⁽¹⁾	0.72	0.76	0.86	1.43	1.54	1.60	2.19	2.40	2.59	ns
PCI33_3 ⁽¹⁾	1.28	1.41	1.65	2.71	3.08	3.52	3.47	3.94	4.51	ns
HSUL_12	0.63	0.64	0.71	1.77	1.90	2.00	2.53	2.76	2.99	ns
DIFF_HSUL_12	0.58	0.61	0.70	1.55	1.68	1.78	2.31	2.54	2.77	ns
HSTL_I_S	0.61	0.64	0.73	1.55	1.69	1.80	2.31	2.55	2.79	ns
HSTL_II_S	0.61	0.64	0.73	1.21	1.34	1.43	1.97	2.20	2.42	ns
HSTL_I_18_S	0.64	0.67	0.76	1.28	1.39	1.45	2.04	2.25	2.44	ns
HSTL_II_18_S	0.64	0.67	0.76	1.18	1.31	1.40	1.94	2.17	2.39	ns
DIFF_HSTL_I_S	0.63	0.67	0.77	1.42	1.54	1.61	2.18	2.40	2.60	ns
DIFF_HSTL_II_S	0.63	0.67	0.77	1.15	1.24	1.27	1.91	2.10	2.26	ns
DIFF_HSTL_I_18_S	0.65	0.69	0.78	1.27	1.38	1.43	2.03	2.24	2.42	ns
DIFF_HSTL_II_18_S	0.65	0.69	0.78	1.14	1.23	1.26	1.90	2.09	2.25	ns
HSTL_I_F	0.61	0.64	0.73	1.10	1.19	1.23	1.86	2.05	2.22	ns

Table 20: 1.8V IOB High Performance (HP) Switching Characteristics

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units
	Speed Grade			Speed Grade			Speed Grade			
	-3	-2/-2L/-2G	-1	-3	-2/-2L/-2G	-1	-3	-2/-2L/-2G	-1	
LVDS	0.75	0.79	0.92	1.05	1.17	1.24	1.68	1.92	2.06	ns
HSUL_12	0.69	0.72	0.82	1.65	1.84	2.05	2.29	2.59	2.87	ns
DIFF_HSUL_12	0.69	0.72	0.82	1.65	1.84	2.05	2.29	2.59	2.87	ns
HSTL_I_S	0.68	0.72	0.82	1.15	1.28	1.38	1.79	2.03	2.20	ns
HSTL_II_S	0.68	0.72	0.82	1.05	1.17	1.26	1.69	1.93	2.08	ns
HSTL_I_18_S	0.70	0.72	0.82	1.12	1.24	1.34	1.75	2.00	2.16	ns
HSTL_II_18_S	0.70	0.72	0.82	1.06	1.18	1.26	1.70	1.94	2.08	ns
HSTL_I_12_S	0.68	0.72	0.82	1.14	1.27	1.37	1.78	2.02	2.20	ns
HSTL_I_DCI_S	0.68	0.72	0.82	1.11	1.23	1.33	1.74	1.99	2.15	ns
HSTL_II_DCI_S	0.68	0.72	0.82	1.05	1.17	1.26	1.69	1.93	2.08	ns
HSTL_II_T_DCI_S	0.70	0.72	0.82	1.15	1.28	1.38	1.78	2.03	2.20	ns
HSTL_I_DCI_18_S	0.70	0.72	0.82	1.11	1.23	1.33	1.74	1.99	2.15	ns
HSTL_II_DCI_18_S	0.70	0.72	0.82	1.05	1.16	1.24	1.69	1.92	2.06	ns
HSTL_II_T_DCI_18_S	0.70	0.72	0.82	1.11	1.23	1.33	1.74	1.99	2.15	ns
DIFF_HSTL_I_S	0.75	0.79	0.92	1.15	1.28	1.38	1.79	2.03	2.20	ns
DIFF_HSTL_II_S	0.75	0.79	0.92	1.05	1.17	1.26	1.69	1.93	2.08	ns
DIFF_HSTL_I_DCI_S	0.75	0.79	0.92	1.15	1.28	1.38	1.78	2.03	2.20	ns
DIFF_HSTL_II_DCI_S	0.75	0.79	0.92	1.05	1.17	1.26	1.69	1.93	2.08	ns
DIFF_HSTL_I_18_S	0.75	0.79	0.92	1.12	1.24	1.34	1.75	2.00	2.16	ns
DIFF_HSTL_II_18_S	0.75	0.79	0.92	1.06	1.18	1.26	1.70	1.94	2.08	ns
DIFF_HSTL_I_DCI_18_S	0.75	0.79	0.92	1.11	1.23	1.33	1.74	1.99	2.15	ns
DIFF_HSTL_II_DCI_18_S	0.75	0.79	0.92	1.05	1.16	1.24	1.69	1.92	2.06	ns
DIFF_HSTL_II_T_DCI_18_S	0.75	0.79	0.92	1.11	1.23	1.33	1.74	1.99	2.15	ns
HSTL_I_F	0.68	0.72	0.82	1.02	1.14	1.22	1.66	1.90	2.04	ns
HSTL_II_F	0.68	0.72	0.82	0.97	1.08	1.15	1.61	1.84	1.97	ns
HSTL_I_18_F	0.70	0.72	0.82	1.04	1.16	1.24	1.68	1.91	2.06	ns
HSTL_II_18_F	0.70	0.72	0.82	0.98	1.09	1.16	1.62	1.85	1.98	ns
HSTL_I_12_F	0.68	0.72	0.82	1.02	1.13	1.21	1.65	1.88	2.03	ns
HSTL_I_DCI_F	0.68	0.72	0.82	1.04	1.16	1.24	1.67	1.91	2.06	ns
HSTL_II_DCI_F	0.68	0.72	0.82	0.97	1.08	1.15	1.61	1.84	1.97	ns
HSTL_II_T_DCI_F	0.70	0.72	0.82	1.02	1.14	1.22	1.66	1.90	2.04	ns
HSTL_I_DCI_18_F	0.70	0.72	0.82	1.04	1.16	1.24	1.67	1.91	2.06	ns
HSTL_II_DCI_18_F	0.70	0.72	0.82	0.98	1.09	1.16	1.61	1.85	1.98	ns
HSTL_II_T_DCI_18_F	0.70	0.72	0.82	1.04	1.16	1.24	1.67	1.91	2.06	ns
DIFF_HSTL_I_F	0.75	0.79	0.92	1.02	1.14	1.22	1.66	1.90	2.04	ns
DIFF_HSTL_II_F	0.75	0.79	0.92	0.97	1.08	1.15	1.61	1.84	1.97	ns
DIFF_HSTL_I_DCI_F	0.75	0.79	0.92	1.02	1.14	1.22	1.66	1.90	2.04	ns
DIFF_HSTL_II_DCI_F	0.75	0.79	0.92	0.97	1.08	1.15	1.61	1.84	1.97	ns

Input Serializer/Deserializer Switching Characteristics

Table 24: ISERDES Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
Setup/Hold for Control Lines					
$T_{ISCK_BITSLIP}/T_{ISCK_BITSLIP}$	BITSLIP pin setup/hold with respect to CLKDIV	0.01/0.12	0.02/0.13	0.02/0.15	ns
$T_{ISCK_CE}/T_{ISCK_CE}^{(2)}$	CE pin setup/hold with respect to CLK (for CE1)	0.39/−0.02	0.44/−0.02	0.63/−0.02	ns
$T_{ISCK_CE2}/T_{ISCK_CE2}^{(2)}$	CE pin setup/hold with respect to CLKDIV (for CE2)	−0.12/0.29	−0.12/0.31	−0.12/0.35	ns
Setup/Hold for Data Lines					
T_{ISDCK_D}/T_{ISCKD_D}	D pin setup/hold with respect to CLK	−0.02/0.11	−0.02/0.12	−0.02/0.15	ns
$T_{ISDCK_DDL}/T_{ISCKD_DDL}$	DDL pin setup/hold with respect to CLK (using IDELAY) ⁽¹⁾	−0.02/0.11	−0.02/0.12	−0.02/0.15	ns
$T_{ISDCK_D_DDR}/T_{ISCKD_D_DDR}$	D pin setup/hold with respect to CLK at DDR mode	−0.02/0.11	−0.02/0.12	−0.02/0.15	ns
$T_{ISDCK_DDL_DDR}/T_{ISCKD_DDL_DDR}$	D pin setup/hold with respect to CLK at DDR mode (using IDELAY) ⁽¹⁾	0.11/0.11	0.12/0.12	0.15/0.15	ns
Sequential Delays					
T_{ISCKO_Q}	CLKDIV to out at Q pin	0.46	0.47	0.58	ns
Propagation Delays					
T_{ISDO_DO}	D input to DO output pin	0.09	0.10	0.12	ns

Notes:

- Recorded at 0 tap value.
- T_{ISCK_CE2} and T_{ISCK_CE2} are reported as T_{ISCK_CE}/T_{ISCK_CE} in the timing report.

Output Serializer/Deserializer Switching Characteristics

Table 25: OSERDES Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
Setup/Hold					
T _{OSDCK_D} /T _{OSCKD_D}	D input setup/hold with respect to CLKDIV	0.37/0.02	0.40/0.02	0.55/0.02	ns
T _{OSDCK_T} /T _{OSCKD_T} ⁽¹⁾	T input setup/hold with respect to CLK	0.49/−0.15	0.56/−0.15	0.68/−0.15	ns
T _{OSDCK_T2} /T _{OSCKD_T2} ⁽¹⁾	T input setup/hold with respect to CLKDIV	0.27/−0.15	0.30/−0.15	0.34/−0.15	ns
T _{OSCCK_OCE} /T _{OSCKC_OCE}	OCE input setup/hold with respect to CLK	0.28/0.03	0.29/0.03	0.45/0.03	ns
T _{OSCCK_S}	SR (Reset) input setup with respect to CLKDIV	0.41	0.46	0.75	ns
T _{OSCCK_TCE} /T _{OSCKC_TCE}	TCE input setup/hold with respect to CLK	0.28/0.01	0.30/0.01	0.45/0.01	ns
Sequential Delays					
T _{OSCKO_OQ}	Clock to out from CLK to OQ	0.35	0.37	0.42	ns
T _{OSCKO_TQ}	Clock to out from CLK to TQ	0.41	0.43	0.49	ns
Combinatorial					
T _{OSDO_TTQ}	T input to TQ Out	0.73	0.81	0.97	ns

Notes:

- T_{OSDCK_T2} and T_{OSCKD_T2} are reported as T_{OSDCK_T}/T_{OSCKD_T} in the timing report.

Input/Output Delay Switching Characteristics

Table 26: Input/Output Delay Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
IDELAYCTRL					
T _{DLYCCO_RDY}	Reset to ready for IDELAYCTRL	3.22	3.22	3.22	μs
F _{IDELAYCTRL_REF}	Attribute REFCLK frequency = 200.0 ⁽¹⁾	200	200	200	MHz
	Attribute REFCLK frequency = 300.0 ⁽¹⁾	300	300	N/A	MHz
IDELAYCTRL_REF_PRECISION	REFCLK precision	±10	±10	±10	MHz
T _{IDELAYCTRL_RPW}	Minimum reset pulse width	52.00	52.00	52.00	ns
IDELAY/ODELAY					
T _{IDELAYRESOLUTION}	IDELAY/ODELAY chain delay resolution	1/(32 x 2 x F _{REF})			ps
T _{IDELAYPAT_JIT} and T _{ODELAYPAT_JIT}	Pattern dependent period jitter in delay chain for clock pattern. ⁽²⁾	0	0	0	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23) ⁽³⁾	±5	±5	±5	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23) ⁽⁴⁾	±9	±9	±9	ps per tap
T _{IDELAY_CLK_MAX} / T _{ODELAY_CLK_MAX}	Maximum frequency of CLK input to IDELAY/ODELAY	800	800	710	MHz
T _{IDCCK_CE} / T _{IDCKC_CE}	CE pin setup/hold with respect to C for IDELAY	0.11/0.10	0.14/0.12	0.18/0.14	ns
T _{ODCCK_CE} / T _{ODCKC_CE}	CE pin setup/hold with respect to C for ODELAY	0.14/0.03	0.16/0.04	0.19/0.05	ns
T _{IDCCK_INC} / T _{IDCKC_INC}	INC pin setup/hold with respect to C for IDELAY	0.10/0.14	0.12/0.16	0.14/0.20	ns
T _{ODCCK_INC} / T _{ODCKC_INC}	INC pin setup/hold with respect to C for ODELAY	0.10/0.07	0.12/0.08	0.13/0.09	ns
T _{IDCCK_RST} / T _{IDCKC_RST}	RST pin setup/hold with respect to C for IDELAY	0.13/0.08	0.14/0.10	0.16/0.12	ns
T _{ODCCK_RST} / T _{ODCKC_RST}	RST pin setup/hold with respect to C for ODELAY	0.16/0.04	0.19/0.06	0.24/0.08	ns
T _{IDDO_IDATAIN}	Propagation delay through IDELAY	Note 5	Note 5	Note 5	ps
T _{ODDO_ODATAIN}	Propagation delay through ODELAY	Note 5	Note 5	Note 5	ps

Notes:

1. Average tap delay at 200 MHz = 78 ps, at 300 MHz = 52 ps.
2. When HIGH_PERFORMANCE mode is set to TRUE or FALSE.
3. When HIGH_PERFORMANCE mode is set to TRUE.
4. When HIGH_PERFORMANCE mode is set to FALSE.
5. Delay depends on IDELAY/ODELAY tap setting. See the timing report for actual values.

CLB Distributed RAM Switching Characteristics (SLICEM Only)*Table 29: CLB Distributed RAM Switching Characteristics*

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
Sequential Delays					
T _{SHCKO} ⁽¹⁾	Clock to A – B outputs	0.68	0.70	0.85	ns, Max
T _{SHCKO_1}	Clock to AMUX – BMUX outputs	0.91	0.95	1.15	ns, Max
Setup and Hold Times Before/After Clock CLK					
T _{DS_LRAM} /T _{DH_LRAM}	A – D inputs to CLK	0.45/0.23	0.45/0.24	0.54/0.27	ns, Min
T _{AS_LRAM} /T _{AH_LRAM}	Address An inputs to clock	0.13/0.50	0.14/0.50	0.17/0.58	ns, Min
	Address An inputs through MUXs and/or carry logic to clock	0.40/0.16	0.42/0.17	0.52/0.23	ns, Min
T _{WS_LRAM} /T _{WH_LRAM}	WE input to clock	0.29/0.09	0.30/0.09	0.36/0.09	ns, Min
T _{CECK_LRAM} /T _{CKCE_LRAM}	CE input to CLK	0.29/0.09	0.30/0.09	0.37/0.09	ns, Min
Clock CLK					
T _{MPW}	Minimum pulse width	0.68	0.77	0.91	ns, Min
T _{MCP}	Minimum clock period	1.35	1.54	1.82	ns, Min

Notes:

1. T_{SHCKO} also represents the CLK to XMUX output. Refer to the timing report for the CLK to XMUX path.

CLB Shift Register Switching Characteristics (SLICEM Only)*Table 30: CLB Shift Register Switching Characteristics*

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
Sequential Delays					
T _{REG}	Clock to A – D outputs	0.96	0.98	1.20	ns, Max
T _{REG_MUX}	Clock to AMUX – DMUX output	1.19	1.23	1.50	ns, Max
T _{REG_M31}	Clock to DMUX output via M31 output	0.89	0.91	1.10	ns, Max
Setup and Hold Times Before/After Clock CLK					
T _{WS_SHFREG} /T _{WH_SHFREG}	WE input	0.26/0.09	0.27/0.09	0.33/0.09	ns, Min
T _{CECK_SHFREG} /T _{CKCE_SHFREG}	CE input to CLK	0.27/0.09	0.28/0.09	0.33/0.09	ns, Min
T _{DS_SHFREG} /T _{DH_SHFREG}	A – D inputs to CLK	0.28/0.26	0.28/0.26	0.33/0.30	ns, Min
Clock CLK					
T _{MPW_SHFREG}	Minimum pulse width	0.55	0.65	0.78	ns, Min

Block RAM and FIFO Switching Characteristics

Table 31: Block RAM and FIFO Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
Block RAM and FIFO Clock-to-Out Delays					
T _{RCKO_DO} and T _{RCKO_DO_REG} ⁽¹⁾	Clock CLK to DOUT output (without output register) ⁽²⁾⁽³⁾	1.57	1.80	2.08	ns, Max
	Clock CLK to DOUT output (with output register) ⁽⁴⁾⁽⁵⁾	0.54	0.63	0.75	ns, Max
T _{RCKO_DO_ECC} and T _{RCKO_DO_ECC_REG}	Clock CLK to DOUT output with ECC (without output register) ⁽²⁾⁽³⁾	2.35	2.58	3.26	ns, Max
	Clock CLK to DOUT output with ECC (with output register) ⁽⁴⁾⁽⁵⁾	0.62	0.69	0.80	ns, Max
T _{RCKO_DO_CASCOUT} and T _{RCKO_DO_CASCOUT_REG}	Clock CLK to DOUT output with Cascade (without output register) ⁽²⁾	2.21	2.45	2.80	ns, Max
	Clock CLK to DOUT output with Cascade (with output register) ⁽⁴⁾	0.98	1.08	1.24	ns, Max
T _{RCKO_FLAGS}	Clock CLK to FIFO flags outputs ⁽⁶⁾	0.65	0.74	0.89	ns, Max
T _{RCKO_POINTERS}	Clock CLK to FIFO pointers outputs ⁽⁷⁾	0.79	0.87	0.98	ns, Max
T _{RCKO_PARITY_ECC}	Clock CLK to ECCPARITY in ECC encode only mode	0.66	0.72	0.80	ns, Max
T _{RCKO_SDBIT_ECC} and T _{RCKO_SDBIT_ECC_REG}	Clock CLK to BITERR (without output register)	2.17	2.38	3.01	ns, Max
	Clock CLK to BITERR (with output register)	0.57	0.65	0.76	ns, Max
T _{RCKO_RDADDR_ECC} and T _{RCKO_RDADDR_ECC_REG}	Clock CLK to RDADDR output with ECC (without output register)	0.64	0.74	0.90	ns, Max
	Clock CLK to RDADDR output with ECC (with output register)	0.71	0.79	0.92	ns, Max
Setup and Hold Times Before/After Clock CLK					
T _{RCKC_ADDRA} /T _{RCKC_ADDRA}	ADDR inputs ⁽⁸⁾	0.38/0.27	0.42/0.28	0.48/0.31	ns, Min
T _{RDCK_DI_WF_NC} / T _{RCKD_DI_WF_NC}	Data input setup/hold time when block RAM is configured in WRITE_FIRST or NO_CHANGE mode ⁽⁹⁾	0.49/0.51	0.55/0.53	0.63/0.57	ns, Min
T _{RDCK_DI_RF} /T _{RCKD_DI_RF}	Data input setup/hold time when block RAM is configured in READ_FIRST mode ⁽⁹⁾	0.17/0.25	0.19/0.29	0.21/0.35	ns, Min
T _{RDCK_DI_ECC} /T _{RCKD_DI_ECC}	DIN inputs with block RAM ECC in standard mode ⁽⁹⁾	0.42/0.37	0.47/0.39	0.53/0.43	ns, Min
T _{RDCK_DI_ECCW} /T _{RCKD_DI_ECCW}	DIN inputs with block RAM ECC encode only ⁽⁹⁾	0.79/0.37	0.87/0.39	0.99/0.43	ns, Min
T _{RDCK_DI_ECC_FIFO} / T _{RCKD_DI_ECC_FIFO}	DIN inputs with FIFO ECC in standard mode ⁽⁹⁾	0.89/0.47	0.98/0.50	1.12/0.54	ns, Min
T _{RCKC_INJECTBITERR} / T _{RCKC_INJECTBITERR}	Inject single/double bit error in ECC mode	0.49/0.30	0.55/0.31	0.63/0.34	ns, Min
T _{RCKC_EN} /T _{RCKC_EN}	Block RAM Enable (EN) input	0.30/0.17	0.33/0.18	0.38/0.20	ns, Min
T _{RCKC_REGCE} /T _{RCKC_REGCE}	CE input of output register	0.21/0.13	0.25/0.13	0.31/0.14	ns, Min
T _{RCKC_RSTREG} /T _{RCKC_RSTREG}	Synchronous RSTREG input	0.25/0.06	0.27/0.06	0.29/0.06	ns, Min
T _{RCKC_RSTRAM} /T _{RCKC_RSTRAM}	Synchronous RSTRAM input	0.27/0.35	0.29/0.37	0.31/0.39	ns, Min
T _{RCKC_WEA} /T _{RCKC_WEA}	Write Enable (WE) input (Block RAM only)	0.38/0.15	0.41/0.16	0.46/0.17	ns, Min
T _{RCKC_WREN} /T _{RCKC_WREN}	WREN FIFO inputs	0.39/0.25	0.39/0.30	0.40/0.37	ns, Min
T _{RCKC_RDEN} /T _{RCKC_RDEN}	RDEN FIFO inputs	0.36/0.26	0.36/0.30	0.37/0.37	ns, Min
Reset Delays					
T _{RCO_FLAGS}	Reset RST to FIFO flags/pointers ⁽¹⁰⁾	0.76	0.83	0.93	ns, Max
T _{RREC_RST} /T _{RREM_RST}	FIFO reset recovery and removal timing ⁽¹¹⁾	1.59/–0.68	1.76/–0.68	2.01/–0.68	ns, Max

Table 42: Clock-Capable Clock Input to Output Delay With MMCM

Symbol	Description	Device	Speed Grade			Units
			-3	-2/-2L/-2G	-1	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>with</i> MMCM.						
T _{ICKOFMMCMCC}	Clock-capable clock input and OUTFF <i>with</i> MMCM	XC7V585T	1.07	1.07	1.07	ns
		XC7V2000T	N/A	0.82	0.82	ns
		XC7VX330T	1.01	1.01	1.01	ns
		XC7VX415T	1.07	1.07	1.07	ns
		XC7VX485T	0.91	0.91	0.91	ns
		XC7VX550T	0.97	0.97	0.97	ns
		XC7VX690T	1.07	1.07	1.07	ns
		XC7VX980T	N/A	0.96	0.96	ns
		XC7VX1140T	N/A	0.82	0.82	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net in a single SLR.
2. MMCM output jitter is already included in the timing calculation.

Table 43: Clock-Capable Clock Input to Output Delay With PLL

Symbol	Description	Device	Speed Grade			Units
			-3	-2/-2L/-2G	-1	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>with</i> PLL.						
T _{ICKOFPLLCC}	Clock-capable clock input and OUTFF <i>with</i> PLL	XC7V585T	0.96	0.96	0.96	ns
		XC7V2000T	N/A	0.71	0.71	ns
		XC7VX330T	0.90	0.90	0.90	ns
		XC7VX415T	0.96	0.96	0.96	ns
		XC7VX485T	0.80	0.80	0.80	ns
		XC7VX550T	0.86	0.86	0.86	ns
		XC7VX690T	0.96	0.96	0.96	ns
		XC7VX980T	N/A	0.85	0.85	ns
		XC7VX1140T	N/A	0.71	0.71	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net in a single SLR.
2. PLL output jitter is already included in the timing calculation.

Table 44: Pin-to-Pin, Clock-to-Out using BUFIO

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>with</i> BUFIO.					
T _{ICKOFCS}	Clock-to-out of I/O clock for HR I/O banks	4.93	5.52	6.20	ns
	Clock-to-out of I/O clock for HP I/O banks	4.85	5.44	6.11	ns

GTX Transceiver Specifications

GTX Transceiver DC Input and Output Levels

Table 51 summarizes the DC specifications of the GTX transceivers in Virtex-7 T and XT FPGAs. Consult the *7 Series FPGAs GTX/GTH Transceiver User Guide* (UG476) for further details.

Table 51: GTX Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
DV _{PPOUT}	Differential peak-to-peak output voltage ⁽¹⁾	Transmitter output swing is set to maximum setting	–	–	1000	mV
V _{CMOUTDC}	DC common mode output voltage.	Equation based	$V_{MGTAVTT} - DV_{PPOUT}/4$			mV
R _{OUT}	Differential output resistance		–	100	–	Ω
T _{OSKEW}	Transmitter output pair (TXP and TXN) intra-pair skew		–	2	12	ps
DV _{PPIN}	Differential peak-to-peak input voltage (external AC coupled)	>10.3125 Gb/s	150	–	1250	mV
		6.6 Gb/s to 10.3125 Gb/s	150	–	1250	mV
		≤ 6.6 Gb/s	150	–	2000	mV
V _{IN}	Absolute input voltage	DC coupled $V_{MGTAVTT} = 1.2V$	–200	–	$V_{MGTAVTT}$	mV
V _{CMIN}	Common mode input voltage	DC coupled $V_{MGTAVTT} = 1.2V$	–	$2/3 V_{MGTAVTT}$	–	mV
R _{IN}	Differential input resistance		–	100	–	Ω
C _{EXT}	Recommended external AC coupling capacitor ⁽²⁾		–	100	–	nF

Notes:

- The output swing and preemphasis levels are programmable using the attributes discussed in the *7 Series FPGAs GTX/GTH Transceiver User Guide* (UG476), and can result in values lower than reported in this table.
- Other values can be used as appropriate to conform to specific protocols and standards.

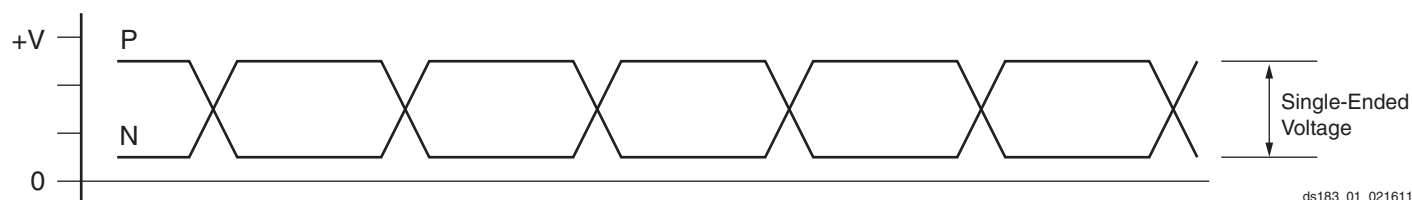


Figure 1: Single-Ended Peak-to-Peak Voltage

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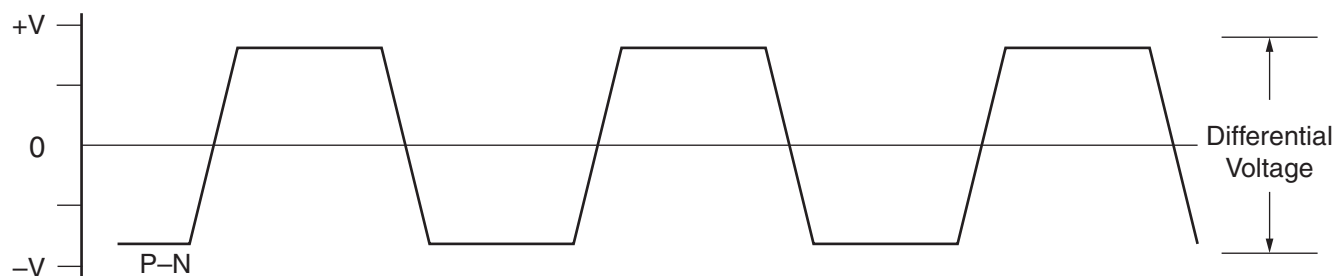


Figure 2: Differential Peak-to-Peak Voltage

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Table 55: GTX Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range	-3 speed grade	60	–	700	MHz
		All other speed grades	60	–	670	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	–	200	–	ps
T_{FCLK}	Reference clock fall time	80% – 20%	–	200	–	ps
T_{DCREF}	Reference clock duty cycle	Transceiver PLL only	40	50	60	%

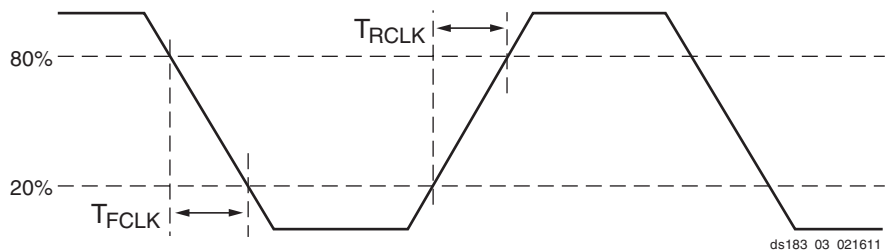


Figure 3: Reference Clock Timing Parameters

Table 56: GTX Transceiver PLL/Lock Time Adaptation

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
T_{LOCK}	Initial PLL lock		–	–	1	ms
T_{DLOCK}	Clock recovery phase acquisition and adaptation time for decision feedback equalizer (DFE).	After the PLL is locked to the reference clock, this is the time it takes to lock the clock data recovery (CDR) to the data present at the input.	–	50,000	37×10^6	UI
	Clock recovery phase acquisition and adaptation time for low-power mode (LPM) when the DFE is disabled.		–	50,000	2.3×10^6	UI

Table 65: CPRI Protocol Characteristics (GTX Transceivers)

Description	Line Rate (Mb/s)	Min	Max	Units
CPRI Transmitter Jitter Generation				
Total transmitter jitter	614.4	–	0.35	UI
	1228.8	–	0.35	UI
	2457.6	–	0.35	UI
	3072.0	–	0.35	UI
	4915.2	–	0.3	UI
	6144.0	–	0.3	UI
	9830.4	–	Note 1	UI
CPRI Receiver Frequency Jitter Tolerance				
Total receiver jitter tolerance	614.4	0.65	–	UI
	1228.8	0.65	–	UI
	2457.6	0.65	–	UI
	3072.0	0.65	–	UI
	4915.2	0.95	–	UI
	6144.0	0.95	–	UI
	9830.4	Note 1	–	UI

Notes:

1. Tested per SFP+ specification, see Table 64.

GTH Transceiver Specifications

GTH Transceiver DC Input and Output Levels

Table 66 summarizes the DC specifications of the GTH transceivers in Virtex-7 T and XT FPGAs. Consult the *7 Series FPGAs GTX/GTH Transceiver User Guide* (UG476) for further details.

Table 66: GTH Transceiver DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
DV _{PPIN}	Differential peak-to-peak input voltage (external AC coupled)	>10.3125 Gb/s	150	–	1250	mV
		6.6 Gb/s to 10.3125 Gb/s	150	–	1250	mV
		≤ 6.6 Gb/s	150	–	2000	mV
V _{IN}	Absolute input voltage	DC coupled V _{MGTAVTT} = 1.2V	–400	–	V _{MGTAVTT}	mV
V _{CMIN}	Common mode input voltage	DC coupled V _{MGTAVTT} = 1.2V	–	2/3 V _{MGTAVTT}	–	mV
DV _{PPOUT}	Differential peak-to-peak output voltage ⁽¹⁾	Transmitter output swing is set to 1010	–	–	800	mV
V _{CMOUTDC}	Common mode output voltage: DC coupled	Equation based	V _{MGTAVTT} – DV _{PPOUT} /4			mV
V _{CMOUTAC}	Common mode output voltage: AC coupled	Equation based	V _{MGTAVTT} – DV _{PPOUT} /2			mV
R _{IN}	Differential input resistance		–	100	–	Ω
R _{OUT}	Differential output resistance		–	100	–	Ω
T _{OSKEW}	Transmitter output pair (TXP and TXN) intra-pair skew		–	–	10	ps
C _{EXT}	Recommended external AC coupling capacitor ⁽²⁾		–	100	–	nF

Notes:

- The output swing and preemphasis levels are programmable using the attributes discussed in the *7 Series FPGAs GTX/GTH Transceiver User Guide* (UG476), and can result in values lower than reported in this table.
- Other values can be used as appropriate to conform to specific protocols and standards.

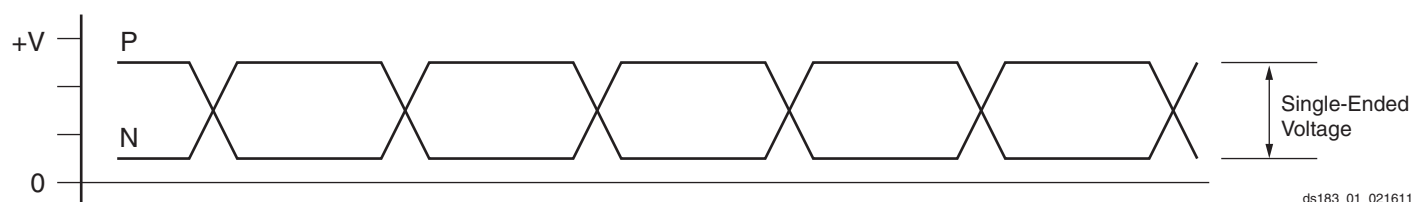


Figure 4: Single-Ended Peak-to-Peak Voltage

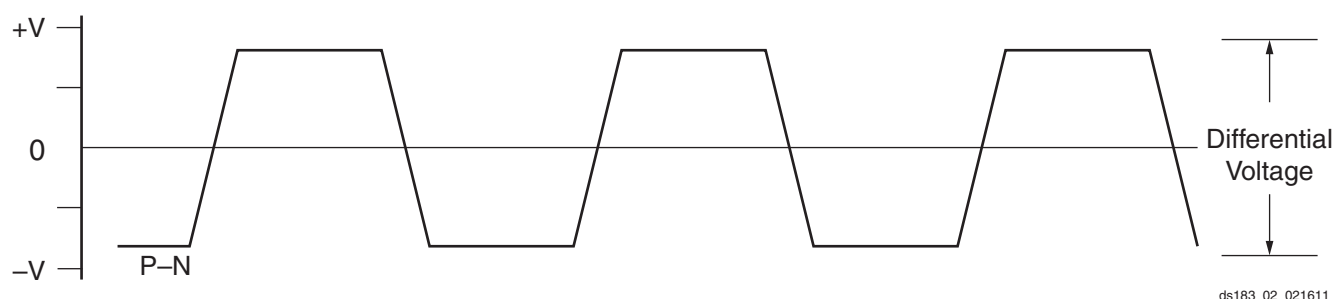


Figure 5: Differential Peak-to-Peak Voltage

Table 74: GTH Transceiver Receiver Switching Characteristics

Symbol	Description		Min	Typ	Max	Units
F _{GTHRX}	Serial data rate	RX oversampler not enabled	0.500	–	F _{GTHMAX}	Gb/s
T _{RXELECIDLE}	Time for RXELEC_IDLE to respond to loss or restoration of data		–	10	–	ns
RX _{OOBVDPP}	OOB detect threshold peak-to-peak		60	–	150	mV
RX _{SST}	Receiver spread-spectrum tracking ⁽¹⁾	Modulated @ 33 KHz	–5000	–	0	ppm
RX _{RL}	Run length (CID)		–	–	512	UI
RX _{PPMTOL}	Data/REFCLK PPM offset tolerance	Bit rates ≤ 6.6 Gb/s	–1250	–	1250	ppm
		Bit rates > 6.6 Gb/s and ≤ 8.0 Gb/s	–700	–	700	ppm
		Bit rates > 8.0 Gb/s	–200	–	200	ppm
SJ Jitter Tolerance ⁽²⁾						
JT_SJ _{13.1}	Sinusoidal jitter (QPLL) ⁽³⁾	13.1 Gb/s	0.3	–	–	UI
JT_SJ _{12.5}	Sinusoidal jitter (QPLL) ⁽³⁾	12.5 Gb/s	0.3	–	–	UI
JT_SJ _{11.3}	Sinusoidal jitter (QPLL) ⁽³⁾	11.3 Gb/s	0.3	–	–	UI
JT_SJ _{10.32_QPLL}	Sinusoidal jitter (QPLL) ⁽³⁾	10.32 Gb/s	0.3	–	–	UI
JT_SJ _{10.32_CPLL}	Sinusoidal jitter (CPLL) ⁽³⁾	10.32 Gb/s	0.3	–	–	UI
JT_SJ _{9.8}	Sinusoidal jitter (QPLL) ⁽³⁾	9.8 Gb/s	0.3	–	–	UI
JT_SJ _{8.0_QPLL}	Sinusoidal jitter (QPLL) ⁽³⁾	8.0 Gb/s	0.44	–	–	UI
JT_SJ _{8.0_CPLL}	Sinusoidal jitter (CPLL) ⁽³⁾	8.0 Gb/s	0.42	–	–	UI
JT_SJ _{6.6_QPLL}	Sinusoidal jitter (QPLL) ⁽³⁾	6.6 Gb/s	0.48	–	–	UI
JT_SJ _{6.6_CPLL}	Sinusoidal jitter (CPLL) ⁽³⁾	6.6 Gb/s	0.44	–	–	UI
JT_SJ _{5.0}	Sinusoidal jitter (CPLL) ⁽³⁾	5.0 Gb/s	0.44	–	–	UI
JT_SJ _{4.25}	Sinusoidal jitter (CPLL) ⁽³⁾	4.25 Gb/s	0.44	–	–	UI
JT_SJ _{3.75}	Sinusoidal jitter (CPLL) ⁽³⁾	3.75 Gb/s	0.44	–	–	UI
JT_SJ _{3.2}	Sinusoidal jitter (CPLL) ⁽³⁾	3.2 Gb/s ⁽⁴⁾	0.45	–	–	UI
JT_SJ _{3.2L}	Sinusoidal jitter (CPLL) ⁽³⁾	3.2 Gb/s ⁽⁵⁾	0.45	–	–	UI
JT_SJ _{2.5}	Sinusoidal jitter (CPLL) ⁽³⁾	2.5 Gb/s ⁽⁶⁾	0.5	–	–	UI
JT_SJ _{1.25}	Sinusoidal jitter (CPLL) ⁽³⁾	1.25 Gb/s ⁽⁷⁾	0.5	–	–	UI
JT_SJ ₅₀₀	Sinusoidal jitter (CPLL) ⁽³⁾	500 Mb/s	0.4	–	–	UI
SJ Jitter Tolerance with Stressed Eye ⁽²⁾						
JT_TJSE _{3.2}	Total jitter with stressed eye ⁽⁸⁾	3.2 Gb/s	0.70	–	–	UI
JT_TJSE _{6.6}		6.6 Gb/s	0.70	–	–	UI
JT_SJSE _{3.2}	Sinusoidal jitter with stressed eye ⁽⁸⁾	3.2 Gb/s	0.1	–	–	UI
JT_SJSE _{6.6}		6.6 Gb/s	0.1	–	–	UI

Notes:

- Using RXOUT_DIV = 1, 2, and 4.
- All jitter values are based on a bit error ratio of 1e^{–12}.
- The frequency of the injected sinusoidal jitter is 80 MHz.
- CPLL frequency at 3.2 GHz and RXOUT_DIV = 2.
- CPLL frequency at 1.6 GHz and RXOUT_DIV = 1.
- CPLL frequency at 2.5 GHz and RXOUT_DIV = 2.
- CPLL frequency at 2.5 GHz and RXOUT_DIV = 4.
- Composite jitter with RX equalizer enabled. DFE disabled.

Table 83: Configuration Switching Characteristics (Cont'd)

Symbol	Description		Virtex-7 T and XT Devices	Speed Grade			Units
				-3	-2/-2L/-2G	-1	
Master/Slave Serial Mode Programming Switching							
T _{DCC} /T _{CCKD}	DIN setup/hold			4.0/0.0	4.0/0.0	4.0/0.0	ns, Min
T _{CCO}	DOUT clock to out			8.0	8.0	8.0	ns, Max
SelectMAP Mode Programming Switching							
T _{SMDCC} /T _{SMCCKD}	D[31:00] setup/hold			4.0/0.0	4.0/0.0	4.0/0.0	ns, Min
T _{SMCSCCK} /T _{SMCCKCS}	CSI_B setup/hold			4.0/0.0	4.0/0.0	4.0/0.0	ns, Min
T _{SMWCCK} /T _{SMCCKW}	RDWR_B setup/hold			10.0/0.0	10.0/0.0	10.0/0.0	ns, Min
T _{SMCKCSO}	CSO_B clock to out (330 Ω pull-up resistor required)			7.0	7.0	7.0	ns, Max
T _{SMCO}	D[31:00] clock to out in readback			8.0	8.0	8.0	ns, Max
F _{RBCK}	Readback frequency	SLR-based		70	70	70	MHz, Max
		All other devices		100	100	100	MHz, Max
Boundary-Scan Port Timing Specifications							
T _{TAPTCK} /T _{TCKTAP}	TMS and TDI setup/hold	SLR-based		9.0/2.0	9.0/2.0	9.0/2.0	ns, Min
		All other devices		3.0/2.0	3.0/2.0	3.0/2.0	ns, Min
T _{TCKTDO}	TCK falling edge to TDO output	SLR-based		17	17	17	ns, Max
		All other devices		7.0	7.0	7.0	ns, Max
F _{TCK}	TCK frequency	SLR-based		20	20	20	MHz, Max
		All other devices		66	66	66	MHz, Max
BPI Master Flash Mode Programming Switching							
T _{BPICCO} ⁽²⁾	A[28:00], RS[1:0], FCS_B, FOE_B, FWE_B, ADV_B clock to out			8.5	8.5	8.5	ns, Max
T _{BPIDCC} /T _{BPICCD}	D[15:00] setup/hold			4.0/0.0	4.0/0.0	4.0/0.0	ns, Min
SPI Master Flash Mode Programming Switching							
T _{SPIDCC} /T _{SPICCD}	D[03:00] setup/hold			3.0/0.0	3.0/0.0	3.0/0.0	ns, Min
T _{SPICCM}	MOSI clock to out			8.0	8.0	8.0	ns, Max
T _{SPICFC}	FCS_B clock to out			8.0	8.0	8.0	ns, Max

Notes:

1. To support longer delays in configuration, use the design solutions described in the *7 Series FPGA Configuration User Guide* ([UG470](#)).
2. Only during configuration, the last edge is determined by a weak pull-up/pull-down resistor in the I/O.

eFUSE Programming Conditions

Table 84 lists the programming conditions specifically for eFUSE. For more information, see the *7 Series FPGA Configuration User Guide* ([UG470](#)).

Table 84: eFUSE Programming Conditions⁽¹⁾

Symbol	Description	Min	Typ	Max	Units
I_{FS}	V_{CCAUX} supply current	–	–	115	mA
t_j	Temperature range	15	–	125	°C

Notes:

1. The FPGA must not be configured during eFUSE programming.